

Flexible all-inorganic photoconductor detectors based on perovskite/hole-conducting layer heterostructures

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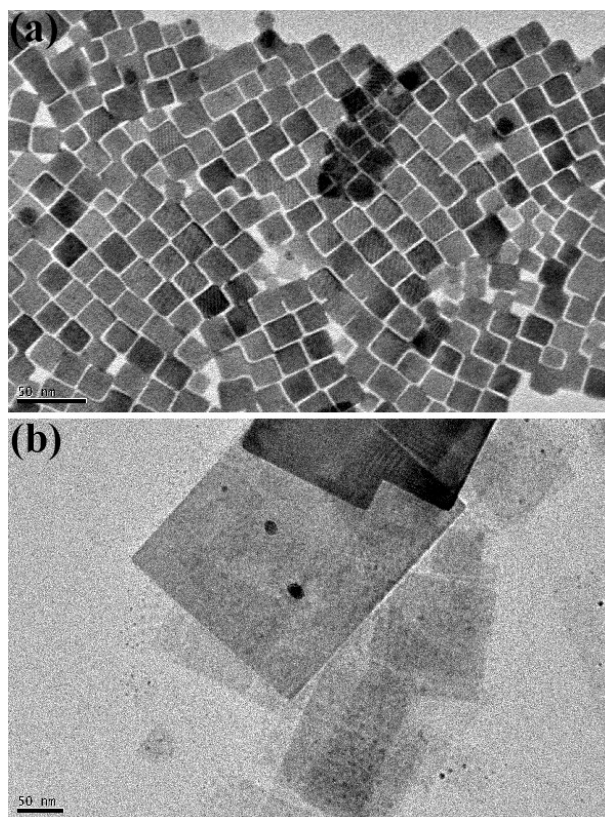


Fig. S1 TEM images of CsPbBr₃ (a) NCs, (b) NSs

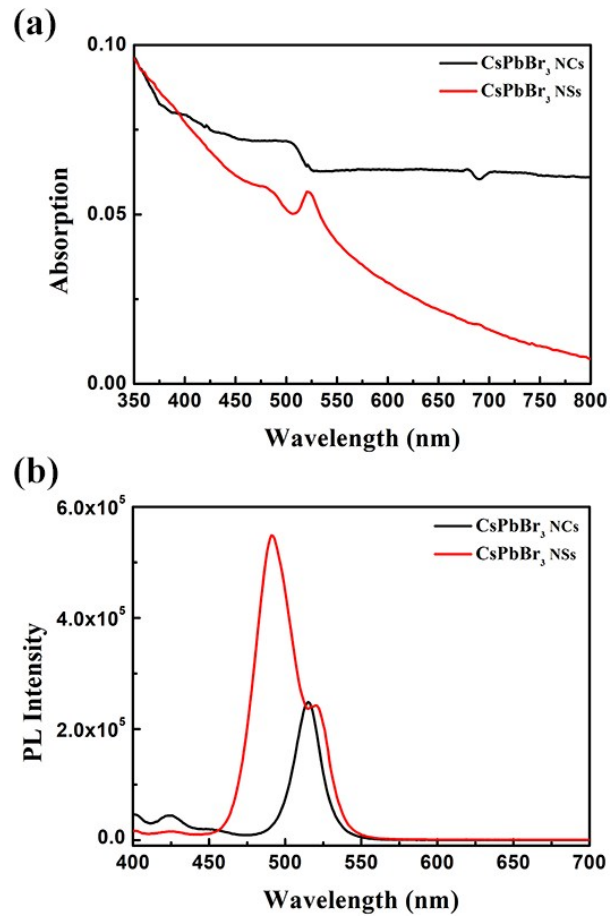


Fig. S2 Optical spectra of CsPbBr₃ NCs and NSs

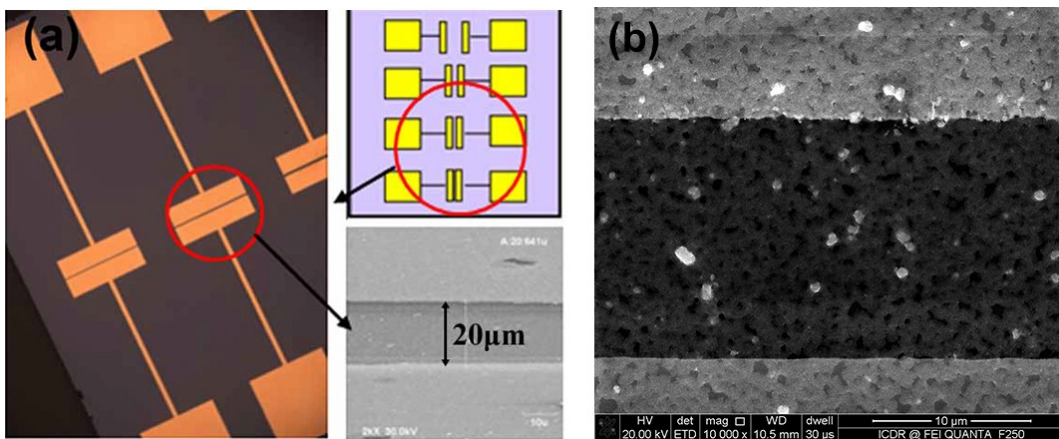


Fig. S3 (a) Microphotograph and (b) SEM image of single chip

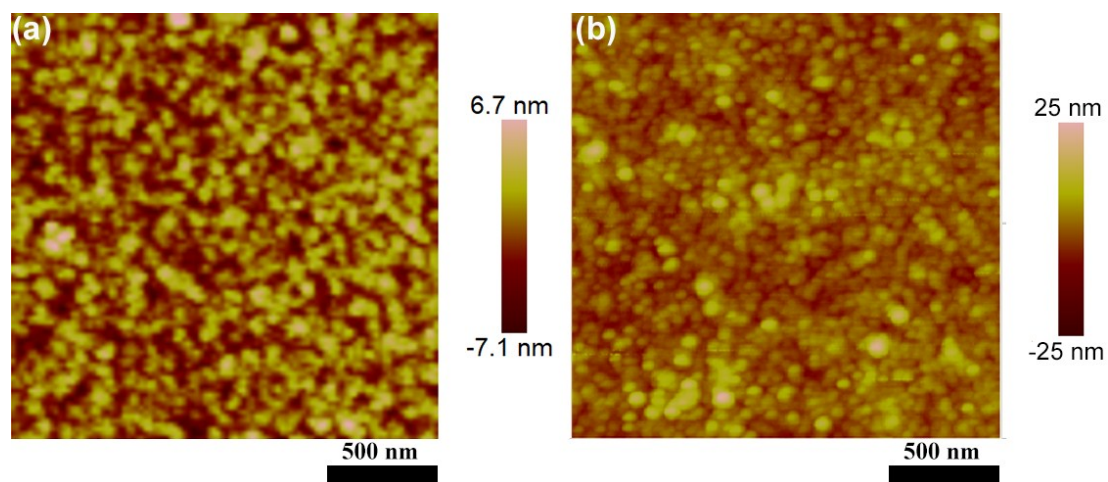


Fig. S4 AFM images of (a) CuSCN and (b) NiO films. It is difficult to distinguish the crystal size of CuSCN film, and obvious grain is observed for NiO film because it is obtained by spin-coating NiO nanocrystal solution. Their corresponding average roughness are 1.5 nm and 6 nm, indicating higher roughness of NiO film.